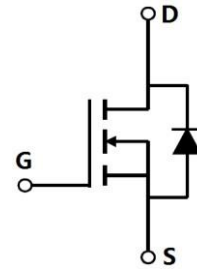


100V N-Channel Enhancement Mode MOSFET

Description

The AP4N10MI uses advanced trench technology to provide excellent $R_{DS(ON)}$, low gate charge and operation with gate voltages as low as 4.5V. This device is suitable for use as a Battery protection or in other Switching application.



General Features

$V_{DS} = 100V$ $I_D = 3.8A$

$R_{DS(ON)} < 240m\Omega$ @ $V_{GS}=10V$



Applicatio

Battery protection

Load switch

Uninterruptible power supply



Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
AP4N10MI	SOT-23-3L	MA5	3000

Absolute Maximum Ratings $T_c=25^\circ C$ unless otherwise noted

Symbol	Parameter	Rating	Units
V_{DS}	Drain-Source Voltage	100	V
V_{GS}	Gate-Source Voltage	± 20	V
I_D	Drain Current – Continuous ($T_c=25^\circ C$)	3.8	A
	Drain Current – Continuous ($T_c=100^\circ C$)	2	A
I_{DM}	Drain Current – Pulsed ¹	8	A
P_D	Power Dissipation ($T_c=25^\circ C$)	3.76	W
	Power Dissipation – Derate above $25^\circ C$	0.5	W/ $^\circ C$
T_{STG}	Storage Temperature Range	-50 to 150	$^\circ C$
T_J	Operating Junction Temperature Range	-50 to 150	$^\circ C$

100V N-Channel Enhancement Mode MOSFET

Thermal Characteristics

Symbol	Parameter	Typ.	Max.	Unit
$R_{\theta JA}$	Thermal Resistance Junction to ambient	---	70	$^{\circ}C/W$
$R_{\theta JC}$	Thermal Resistance Junction to Case	---	30	$^{\circ}C/W$

Electrical Characteristics ($T_J=25^{\circ}C$, unless otherwise noted) Off Characteristics

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{GS}=0V, I_D=250\mu A$	100	---	---	V
$\Delta BV_{DSS}/\Delta T_J$	BV_{DSS} Temperature Coefficient	Reference to $25^{\circ}C, I_D=1mA$	---	0.09	---	$V/^{\circ}C$
I_{DSS}	Drain-Source Leakage Current	$V_{DS}=100V, V_{GS}=0V, T_J=25^{\circ}C$	---	---	1	μA
		$V_{DS}=80V, V_{GS}=0V, T_J=125^{\circ}C$	---	---	10	μA
I_{GSS}	Gate-Source Leakage Current	$V_{GS}=\pm 20V, V_{DS}=0V$	---	---	± 100	nA
$R_{DS(ON)}$	Static Drain-Source On-Resistance	$V_{GS}=10V, I_D=1A$	---	210	240	$m\Omega$
		$V_{GS}=4.5V, I_D=0.5A$	---	240	280	$m\Omega$
$V_{GS(th)}$	Gate Threshold Voltage	$V_{GS}=V_{DS}, I_D=250\mu A$	1.0	1.9	2.5	V
$\Delta V_{GS(th)}$	$V_{GS(th)}$ Temperature Coefficient		---	-5	---	$mV/^{\circ}C$
g_{fs}	Forward Transconductance	$V_{DS}=10V, I_D=2A$	---	2.3	---	S
Q_g	Total Gate Charge ^{2, 3}	$V_{DS}=50V, V_{GS}=10V, I_D=1A$	---	9	18	nC
Q_{gs}	Gate-Source Charge ^{2, 3}		---	2.3	4.6	
Q_{gd}	Gate-Drain Charge ^{2, 3}		---	1.1	2.5	
$T_{d(on)}$	Turn-On Delay Time ^{2, 3}	$V_{DD}=50V, V_{GS}=10V, R_G=3.3, I_D=1A$	---	5.2	10	ns
T_r	Rise Time ^{2, 3}		---	6.8	12	
$T_{d(off)}$	Turn-Off Delay Time ^{2, 3}		---	14.5	28	
T_f	Fall Time ^{2, 3}		---	2.1	5	
C_{iss}	Input Capacitance	$V_{DS}=25V, V_{GS}=0V, F=1MHz$	---	152	200	pF
C_{oss}	Output Capacitance		---	17	20	
C_{rss}	Reverse Transfer Capacitance		---	10	15	
R_g	Gate resistance	$V_{GS}=0V, V_{DS}=0V, F=1MHz$	---	2.8	5.6	

100V N-Channel Enhancement Mode MOSFET

Drain-Source Diode Characteristics and Maximum Ratings

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
I_s	Continuous Source Current	$V_G=V_D=0V$, Force Current	---	---	4	A
I_{SM}	Pulsed Source Current		---	---	8	A
V_{SD}	Diode Forward Voltage	$V_{GS}=0V$, $I_s=1A$, $T_J=25^\circ C$	---	---	1	V
t_{rr}	Reverse Recovery Time ²	$I_s=1A$, $dI/dt=100A/\mu s$ $T_J=25^\circ C$	---	---	---	ns
Q_{rr}	Reverse Recovery Charge ²		---	---	---	nC

Note :

1. Repetitive Rating : Pulsed width limited by maximum junction temperature.
23. . Essentially independent of operating temperature. The data tested by pulsed , pulse width $\leq 300\mu s$, duty cycle $\leq 2\%$.

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

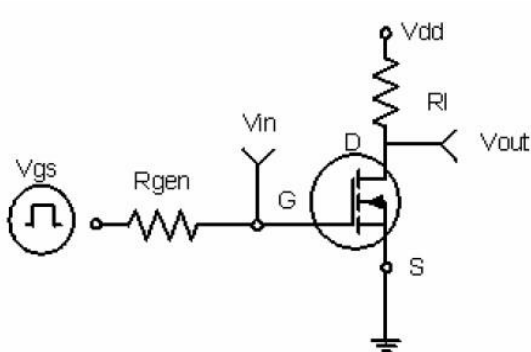


Figure 1: Switching Test Circuit

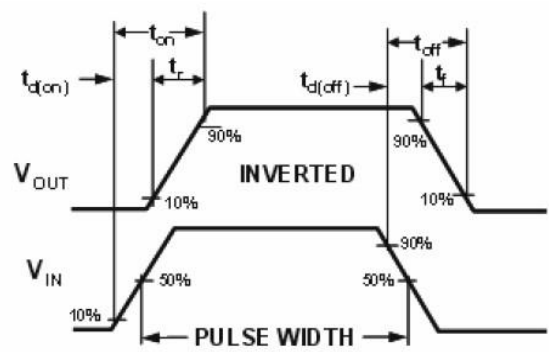


Figure 2: Switching Waveforms

100V N-Channel Enhancement Mode MOSFET

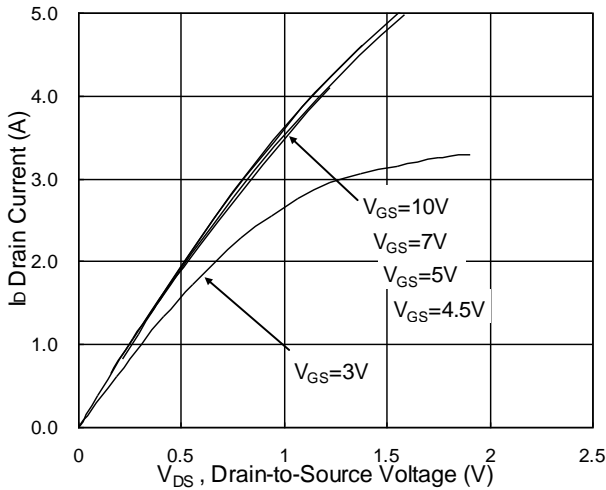


Fig.1 Typical Output Characteristics

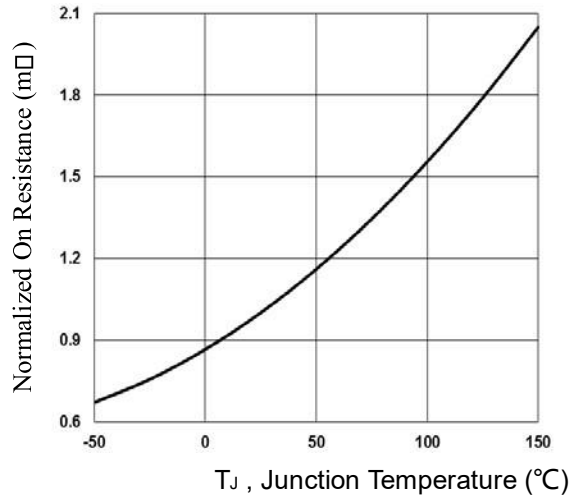


Fig.2 Normalized RDSON vs. TJ

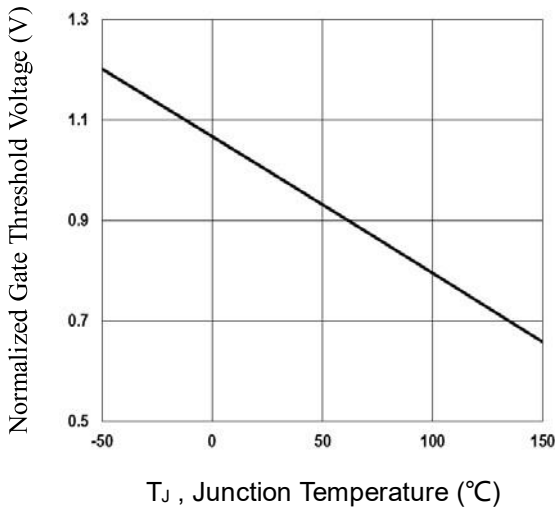


Fig.3 Normalized Vth vs. TJ

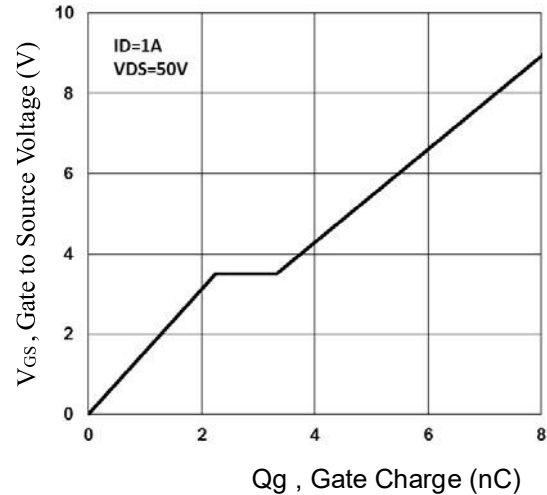


Fig.4 Gate Charge Waveform

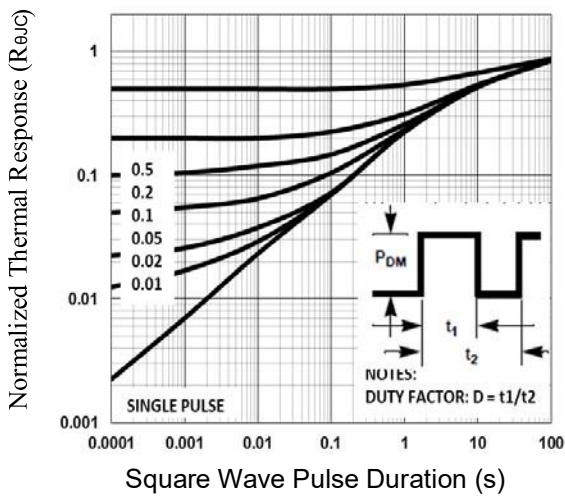


Fig.5 Normalized Transient Impedance

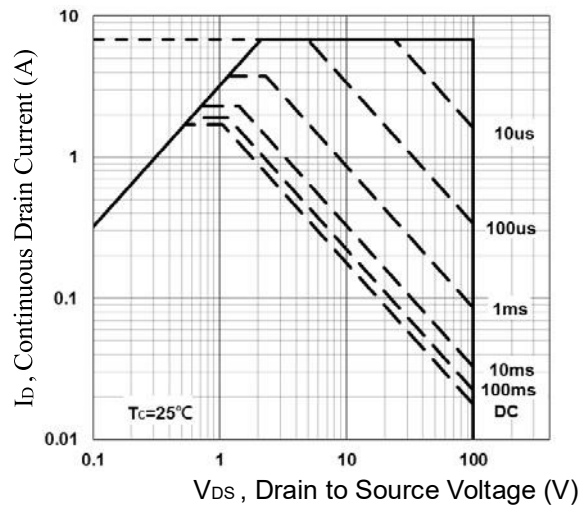
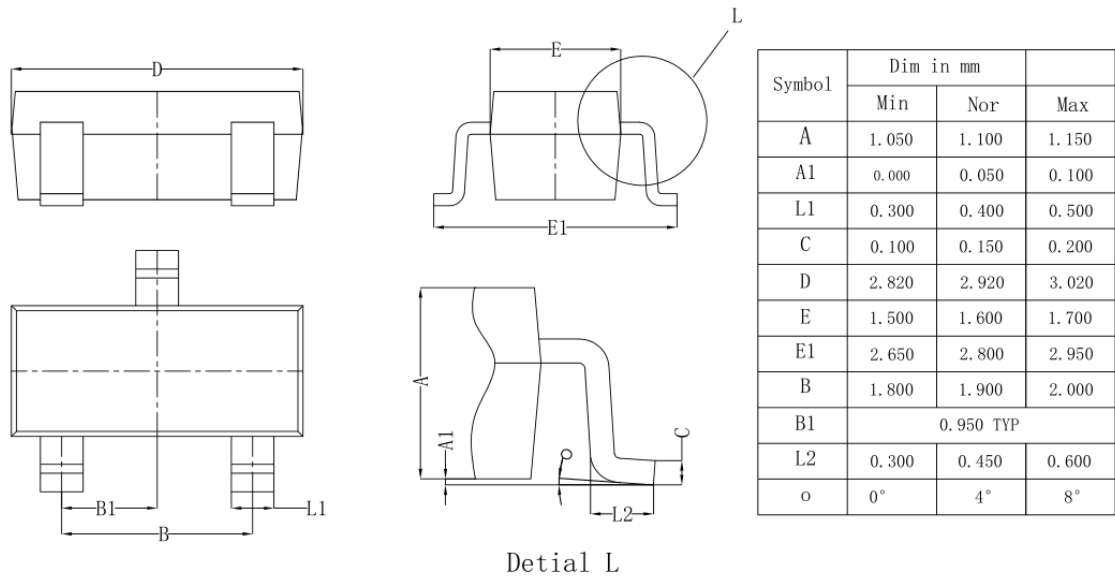


Fig.6 Maximum Safe Operation Area

100V N-Channel Enhancement Mode MOSFET

SOT23-3L Package outline



100V N-Channel Enhancement Mode MOSFET**Attention**

1, Any and all APM Microelectronics products described or contained herein do not have specifications that can handle applications that require extremely high levels of reliability, such as life support systems, aircraft's control systems, or other applications whose failure can be reasonably expected to result in serious physical and/or material damage. Consult with your APM Microelectronics representative nearest you before using any APM Microelectronics products described or contained herein in such applications.

2, APM Microelectronics assumes no responsibility for equipment failures that result from using products at values that exceed, even momentarily, rated values (such as maximum ratings, operating condition ranges, or other parameters) listed in products specifications of any and all APM Microelectronics products described or contained herein.

3, Specifications of any and all APM Microelectronics products described or contained here instipulate the performance, characteristics, and functions of the described products in the independent state, and are not guarantees of the performance, characteristics, and functions of the described products as mounted in the customer's products or equipment. To verify symptoms and states that cannot be evaluated in an independent device, the customer should always evaluate and test devices mounted in the customer's products or equipment.

4, APM Microelectronics Semiconductor CO., LTD. strives to supply high quality high reliability products. However, any and all semiconductor products fail with some probability. It is possible that these probabilistic failures could give rise to accidents or events that could endanger human lives that could give rise to smoke or fire, or that could cause damage to other property. When designing equipment, adopt safety measures so that these kinds of accidents or events cannot occur. Such measures include but are not limited to protective circuits and error prevention circuits for safe design, redundant design, and structural design.

5, In the event that any or all APM Microelectronics products (including technical data, services) described or contained herein are controlled under any of applicable local export control laws and regulations, such products must not be exported without obtaining the export license from the authorities concerned in accordance with the above law.

6, No part of this publication may be reproduced or transmitted in any form or by any means, electronic or mechanical, including photocopying and recording, or any information storage or retrieval system, or otherwise, without the prior written permission of APM Microelectronics Semiconductor CO., LTD.

7, Information (including circuit diagrams and circuit parameters) herein is for example only; it is not guaranteed for volume production. APM Microelectronics believes information herein is accurate and reliable, but no guarantees are made or implied regarding its use or any infringements of intellectual property rights or other rights of third parties.

8, Any and all information described or contained herein are subject to change without notice due to product/technology improvement, etc. When designing equipment, refer to the "Delivery Specification" for the APM Microelectronics product that you intend to use.